

Alternative graphs as a mathematical tool and knowledge representation for diagnosis purposes in digital systems

Ubar, Raimund-Johannes BEC : Baltic Electronics Conference : proceedings of the 4th Biennial Conference, October 9-14, 1994, Tallinn (Estonia). 1 1994 / p. 285-292: ill

An ontology-based intelligent learning object for teaching the basics of digital logic

Robal, Tarmo; Kann, Taavi; Kalja, Ahto 2011 IEEE International Conference on Microelectronic Systems Education (MSE) : 5-6 June 2011, San Diego, CA, USA 2011 / p. 106-107

Application of structurally synthesized binary decision diagrams for timing simulation of digital circuits

Jutman, Artur; Ubar, Raimund-Johannes Proceedings of the Estonian Academy of Sciences. Engineering 2001 / 4, p. 269-288 : ill

BEC : Baltic Electronics Conference : proceedings of the 4th Biennial Conference, October 9-14, 1994, Tallinn (Estonia)
Rang, Toomas; Min, Mart; Ubar, Raimund-Johannes 1994

BEC : Baltic Electronics Conference : proceedings of the 4th Biennial Conference, October 9-14, 1994, Tallinn (Estonia)
1994 https://www.ester.ee/record=b2150914*est

BEC 2002 : proceedings of the 8th Biennial Baltic Electronics Conference : October 6-9, 2002, Tallinn, Estonia
2002 http://www.ester.ee/record=b2150914*est

BEC 2004 : Baltic Electronics Conference : Post-Graduate Student Session : Tallinn University of Technology, October 3-6, 2004, Tallinn, Estonia
2004 https://www.ester.ee/record=b1982896*est

BEC 2004 : proceedings of the 9th Biennial Baltic Electronics Conference : October 3-6, 2004, Tallinn, Estonia
2004 http://www.ester.ee/record=b2150914*est

BEC 2006 : 2006 International Baltic Electronics Conference : Tallinn University of Technology, October 2-4, 2006, Tallinn, Estonia : proceedings of the 10th Biennial Baltic Electronics Conference
2006 http://www.ester.ee/record=b2150914*est

BEC 2008 : 2008 International Biennial Baltic Electronics Conference : proceedings of the 11th Biennial Baltic Electronics Conference : Tallinn University of Technology : October 6-8, 2008, Tallinn, Estonia
2008 http://www.ester.ee/record=b2150914*est

BEC 2010 : 2010 12th Biennial Baltic Electronics Conference : proceedings of the 12th Biennial Baltic Electronics Conference : Tallinn University of Technology : October 4-6, 2010, Tallinn, Estonia
2010 http://www.ester.ee/record=b2150914*est

BEC 2012 : 2012 13th Biennial Baltic Electronics Conference : proceedings of the 13th Biennial Baltic Electronics Conference : October 3-5, 2012, Tallinn, Estonia
2012 http://www.ester.ee/record=b2150914*est

BEC 2014 : 2014 14th Biennial Baltic Electronics Conference : proceedings of the 14th Biennial Baltic Electronics Conference : Tallinn University of Technology, October 6-8, 2014, Tallinn, Estonia
2014 http://www.ester.ee/record=b2150914*est

BEC 2016 : 2016 15th Biennial Baltic Electronics Conference : proceedings of the 15th Biennial Baltic Electronics Conference : Tallinn University of Technology, October 3-5, 2016, Tallinn, Estonia
2016 http://www.ester.ee/record=b2150914*est

BEC'96 : the 5th Biennial Baltic Electronics Conference, October 7-11, 1996, Tallinn, Estonia : proceedings
Rang, Toomas; Min, Mart; Ubar, Raimund-Johannes 1996 https://www.ester.ee/record=b2150914*est

BEC'98 : the 6th Biennial Conference on Electronics and Microsystems Technology, October 7-9, 1998, Tallinn, Estonia : proceedings
1998 https://www.ester.ee/record=b2150914*est

A BIST scheme for testing mixed analogue and digital circuits

Robson, Malcolm; Russel, Gordon BEC'96 : the 5th Biennial Baltic Electronics Conference, October 7-11, 1996, Tallinn, Estonia : proceedings 1996 / p. 183-186: ill

Calculation of testability measures on structurally synthesized binary decision diagrams

Ubar, Raimund-Johannes; Heinlaid, J.; Raik, Jaan; Raun, L. BEC'98 : the 6th Biennial Conference on Electronics and

Microsystems Technology, October 7-9, 1998, Tallinn, Estonia : proceedings 1998 / p. 179-182: ill

Calculation of the diagnosability of digital circuits without using fault models

Ubar, Raimund-Johannes; Kostin, Sergei; Raik, Jaan BEC 2008 : 2008 International Biennial Baltic Electronics Conference : proceedings of the 11th Biennial Baltic Electronics Conference : Tallinn University of Technology : October 6-8, 2008, Tallinn, Estonia 2008 / p. 159-162 : ill

Case study in testing digital systems

Ubar, Raimund-Johannes Baltic electronics 1995 / 1, p. 24-27

A CMOS quadrature baseband frequency synthesizer/modulator

Kosunen, Marko; Vankka, Jouko; Waltari, Mikko; Sumanen, Lauri; Koli, Kimmo; Halonen, Kari BEC'98 : the 6th Biennial Conference on Electronics and Microsystems Technology, October 7-9, 1998, Tallinn, Estonia : proceedings 1998 / p. 219-222: ill

Collaborative distributed computing in the field of digital electronics testing

Ivask, Eero; Devadze, Sergei; Ubar, Raimund-Johannes Balanced Automation Systems for Future Manufacturing Networks : 9th IFIP WG 5.5 International Conference : BASYS 2010 : Valencia, Spain, July 21-23, 2010 : proceedings 2010 / p. 145-152

Collaborative distributed fault simulation for digital electronic circuits

Ivask, Eero; Devadze, Sergei; Ubar, Raimund-Johannes Intelligent Distributed Computing IV : proceedings of the 4th International Symposium on Intelligent Distributed Computing - IDC 2010 : Tangier, Morocco, September 2010 2010 / p. 67-76

Defect-oriented modul-level fault diagnosis in digital circuits

Kostin, Sergei; Ubar, Raimund-Johannes; Raik, Jaan Proceedings of the 2011 IEEE Symposium on Design and Diagnostics of Electronic Circuits and Systems : April 13-15, 2011, Gottbus, Germany 2011 / p. 81-86

Digitaalelektronika : laboratoorse te tööde kogumik

1994 http://www.ester.ee/record=b1065462*est

Digitaalelektronika alused : skeemid : abimaterjal loengute jälgimise ja konspekteerimise hõlbustamiseks

1994 https://www.ester.ee/record=b1065765*est

Digitaali disain - ideest realiseerimiseni

Ellervee, Peeter A & A 2008 / lk. 6-10 : ill https://artiklid.elnet.ee/record=b1021438*est

Digitaalsüsteemide diagnostika

Ubar, Raimund-Johannes 2005 http://www.ester.ee/record=b2097071*est

Digitaalsüsteemide diagnostika Tallinna Tehnikaülikoolis

Ubar, Raimund-Johannes Teadusmõtte Eestis : tehnikateadused 2002 / lk. 107-113 : ill

Digital test in WEB-based environment

Ivask, Eero 2006 https://www.ester.ee/record=b2158119*est

Distributed approach for genetic test generation in the field of digital electronics

Ivask, Eero; Raik, Jaan; Ubar, Raimund-Johannes Intelligent Distributed Computing, Systems and Applications : proceedings of the 2nd International Symposium on Intelligent Distributed Computing : IDC 2008 : Catania, Italy, 2008 2008 / p. 127-136

Dynamic analysis of digital circuits with 5-valued simulation

Ubar, Raimund-Johannes Mixed design of integrated circuits and systems 1998 / p. 187-192: ill
https://link.springer.com/chapter/10.1007/978-1-4615-5651-0_29

Effective self adaptive multiple source localization technique by primal dual interior point method in binary sensor networks

Khan, Muhidul Islam; Xia, Kewen IEEE communications letters 2017 / p. 1119-1122 : ill <https://doi.org/10.1109/LCOMM.2017.2657508>

E-learning environment in the area of digital microelectronics

Jutman, Artur; Sudnitsõn, Aleksander; Ubar, Raimund-Johannes; Wuttke, Heinz-Dietrich ITHET 2004 : proceedings of the Fifth International Conference on Information Technology based Higher Education and Training : 31 May - 2 June, 2004, Istanbul, Turkey 2004 / p. 278-283 : ill

E-learning of digital logic

Robal, Tarmo; Brik, Marina; Aarna, Margit EWME 2006 proceedings : 6th International Workshop on Microelectronics Education : 8-9 June, 2006, Stockholm, Sweden 2006 / p. 120-123 : ill

E-learning tools for teaching self-test of digital electronics

Jutman, Artur; Gramatova, Elena; Pikula, T.; **Ubar, Raimund-Johannes** 15 EAEIE International Conference on Innovation in Education for Electrical and Information Engineering : Sofia, Bulgaria, May 27-29, 2004 2004 / p. 267-272 : ill

E-learning tools for teaching the decomposition based digital synthesis

Sudnitsõn, Aleksander; Kruus, Margus EWME 2006 proceedings : 6th International Workshop on Microelectronics Education : 8-9 June, 2006, Stockholm, Sweden 2006 / p. 63-66 https://pld.ttu.ee/~kruus/EWME_06_sudn.pdf

Fault collapsing in digital circuits using fast fault dominance and equivalence analysis with SSBDDs

Ubar, Raimund-Johannes; Jürimägi, Lembit; Orasson, Elmet; Raik, Jaan VLSI-SoC : Design for Reliability, Security, and Low Power : 23rd IFIP WG 10.5/IEEE International Conference on Very Large Scale Integration, VLSI-SoC 2015 Daejeon, Korea, October 5-7, 2015 : revised selected papers 2016 / p. 23-45 : ill https://doi.org/10.1007/978-3-319-46097-0_2 [Conference Proceedings at Scopus](#) [Article at Scopus](#) [Article at WOS](#)

FPGA platform based digital design education

Mihhailov, Dmitri; Kruus, Margus; Sudnitsõn, Aleksander Proceedings of the 9th International Conference on Computer Systems and Technologies and Workshop for PhD Students in Computing : CompSysTech'2008. Vol. 374, ACM International Conference Proceeding Series 2008 / p. IV.4-1 - IV.4-6 : ill <https://dl.acm.org/doi/pdf/10.1145/1500879.1500938>

FSM decomposition with application to FPGA synthesis

Sudnitsõn, Aleksander; Mihhailov, Dmitri; Kruus, Margus; Tarletski, Konstantin International Conference on Computer Systems and Technologies - CompSysTech'09 : Ruse, Bulgaria 2009 / p. IV.4.1-IV.4.6 <https://dl.acm.org/doi/10.1145/1731740.1731820>

Functional level testability analysis for digital circuits

Ubar, Raimund-Johannes; Kuchcinski, Ktysztof ETC '93 : European Test Conference, Rotterdam, The Netherlands, April 19-22, 1993 1993 / p. 545-546

Hierarchical physical defect reasoning in digital circuits

Kostin, Sergei; Ubar, Raimund-Johannes; Raik, Jaan; Brik, Marina Estonian journal of engineering 2011 / 3, p. 185-200

Hybrid BIST optimization using reseeding and test set compaction

Jervan, Gert; Orasson, Elmet; Kruus, Helena; Ubar, Raimund-Johannes 10th Euromicro Conference on Digital System Design Architectures, Methods and Tools, DSD 2007 : 29-31 August 2007, Lübeck, Germany : proceedings 2007 / p. 596-603 : ill <http://dx.doi.org/10.1109/DSD.2007.4341529>

Hybrid built-in self-test and test generation techniques for digital systems

Jervan, Gert 2005 https://www.ester.ee/record=b2177537*est

Investigating defects in digital circuits by Boolean differential equations

Kruus, Helena; Orasson, Elmet; Robal, Tarmo; Ubar, Raimund-Johannes The 4th International Conference "Distance Learning - Educational Sphere of XXI Century" (DLESC'04) 2004 / p. 432-435

Investigation and development of test generation methods for control part of digital systems

Brik, Marina 2002 http://www.ester.ee/record=b1688656*est

Methods for improving the accuracy and efficiency of fault simulation in digital systems = Meetodid digitaalsüsteemide rikete simuleerimise täpsuse ja efektiivsuse tõstmiseks

Kõusaar, Jaak 2019 <https://digi.lib.ttu.ee/i/?11667>

Mikroprotsessortehnika

Lehtla, Tõnu; Kulmar, Lembit 1995 https://www.ester.ee/record=b1054894*est

Module level defect simulation in digital circuits

Kuzmicz, Wieslaw; Pleskacz, Witold A.; Raik, Jaan; Ubar, Raimund-Johannes Proceedings of the Estonian Academy of Sciences. Engineering 2001 / 4, p. 253-268

Multi-valued simulation of digital circuits with structurally synthesized binary decision diagrams

Ubar, Raimund-Johannes Multiple valued logic. Vol. 4 1998 / p. 141-157

Overview of digital twin platforms for EV applications

Mohamed, Mahmoud Ibrahim Hassanin; Rjabtšikov, Viktor; Zequera, Rolando Antonio Gilbert Sensors 2023 / art. 1414, 15 p. : ill <https://doi.org/10.3390/s23031414> [Journal metrics at Scopus](#) [Article at Scopus](#) [Journal metrics at WOS](#) [Article at WOS](#)

Research environment for teaching digital test

Ivask, Eero; Jutman, Artur; Orasson, Elmet; Raik, Jaan; Ubar, Raimund-Johannes; Wuttke, Heinz-Dietrich Synergies between

Information and Automation : 49. Internationales Wissenschaftliches Kolloquium, 27.-30.9.2004, Technische Universität Ilmenau, Germany. Volume 2 2004 / p. 468-473 : ill https://pld.ttu.ee/dildis/publications/IWK'2004_res_inv.pdf

Selected issues of modeling, verification and testing of digital systems

Jutman, Artur 2004 https://www.ester.ee/record=b1989760*est

Silmade asemel, ehk, Lihtne digitaalne ostsilloskoop arvutile

Sinivee, Veljo Arvutikasutaja 2005 / 2, lk. 10-12 : ill https://artiklid.elnet.ee/record=b1050354*est

Simulation-based verification with APRICOT framework using high-level decision diagrams

Jenihhin, Maksim; Raik, Jaan; Tšepurov, Anton; Ubar, Raimund-Johannes East-West Design & Test Symposium : Moscow, September 18-21, 2009 2009 / p. 13-16 : ill

Sissejuhatus digitaaltehnikasse

Lehtla, Madis 2016 http://www.ester.ee/record=b4618200*est

Test cover calculation in digital systems with word-level decision diagrams

Ubar, Raimund-Johannes; Raik, Jaan; Ivask, Eero; Brik, Marina Вестник Томского государственного университета 2002 / с. 315-319 : ил

Testentwurf für digitale Geräte mit Hilfe der Alternativgraphen

Voolaine, Andrus; Pall, Martin; Plakk, Mari Fehler in Automaten 1989 / S. 31-44 : III

The 7th Biennial Conference on Electronics and Microsystem Technology "Baltic Electronics Conference" : BEC 2000 : October 8 - 11, 2000, Tallinn, Estonia : conference proceedings

2000 https://www.ester.ee/record=b2150914*est

A tool for teaching hierarchical fault diagnosis in digital circuits

Ubar, Raimund-Johannes; Kostin, Sergei; Orasson, Elmet; Evartson, Teet; Brik, Marina Proceedings of 9th European Workshop on Microelectronics Education – EWME'12 : Grenoble, France, May 9-11, 2012 2012 / p. 1-4

Trabajadores de la economía gig en la Unión Europea : hacia un cambio en su clasificación jurídica

Kerikmäe, Tanel; Kajander, Aleks Oskar Johannes Revista CIDOB d'afers internacionals 2022 / p. 117-139
<https://doi.org/10.24241/rcai.2022.131.2.117>

Turbo Tester : a low cost PC-based CAD system for training digital test

Ubar, Raimund-Johannes SampTA'95 : 1995 Workshop on Sampling Theory & Applications, Jurmala, Latvia, September 20-22, 1995 1995

Tööstuses toimuvaid protsesse saab nüüdsest jälgida reaajajas

Shirokova, Veroonika toostusuudised.ee 2022 [Tööstuses toimuvaid protsesse saab nüüdsest jälgida reaajajas](https://www.ester.ee/record=b1242496*est)

Tööstuses toimuvaid protsesse saab nüüdsest jälgida reaajajas

Shirokova, Veroonika Mente et Manu 2022 / lk. 43 https://www.ester.ee/record=b1242496*est

Анализ полноты тестов для цифровых схем на модели альтернативных графов

Kitsnik, Peeter Синтез и диагностика цифровых устройств и систем 1982 / с. 39-51 : илл https://www.ester.ee/record=b1328194*est
<https://digikogu.taltech.ee/et/Item/febd586e-d7fa-4fbd-bf41-40576a75f94b>